

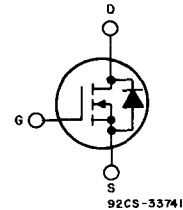
# N-Channel Logic Level Power Field-Effect Transistors (L<sup>2</sup> FET)

8 A, 180 V and 200 V

$r_{DS(on)}$ : 0.5Ω

**Features:**

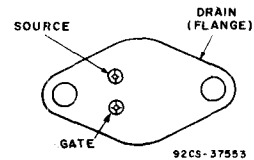
- Design optimized for 5 volt gate drive
- Can be driven directly from Q-MOS, N-MOS, TTL Circuits
- Compatible with automotive drive requirements
- SOA is power-dissipation limited
- Nanosecond switching speeds
- Linear transfer characteristics
- High input impedance
- Majority carrier device



**N-CHANNEL ENHANCEMENT MODE**

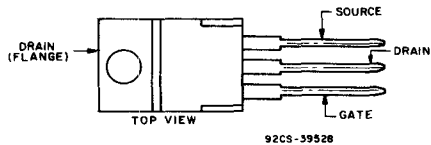
**TERMINAL DESIGNATIONS**

**RFM8N18L  
RFM8N20L**



**JEDEC TO-204AA**

**RFP8N18L  
RFP8N20L**



**JEDEC TO-220AB**

The RFM8N18L and RFM8N20L and the RFP8N18L and RFP8N20L are n-channel enhancement-mode silicon-gate power field-effect transistors specifically designed for use with logic level (5 volt) driving sources in applications such as programmable controllers, automotive switching, and solenoid drivers. This performance is accomplished through a special gate oxide design which provides full rated conduction at gate biases in the 3-5 volt range, thereby facilitating true on-off power control directly from logic circuit supply voltages.

The RFM-series types are supplied in the JEDEC TO-204AA steel package and the RFP-series types in the JEDEC TO-220AB plastic package.

The RFM and RFP series were formerly RCA developmental numbers TA9534 and TA9535.

**MAXIMUM RATINGS, Absolute-Maximum Values (T<sub>C</sub>=25° C):**

	<b>RFM8N18L</b>	<b>RFM8N20L</b>		<b>RFP8N18L</b>	<b>RFP8N20L</b>	
DRAIN-SOURCE VOLTAGE .....	V <sub>DSS</sub>	180	200	180	200	V
DRAIN-GATE VOLTAGE (P <sub>gs</sub> =1 MΩ) .....	V <sub>DGR</sub>	180	200	180	200	V
GATE-SOURCE VOLTAGE .....	V <sub>GS</sub>	±10		±10		V
DRAIN CURRENT, RMS Continuous .....	I <sub>D</sub>	8		8		A
Pulsed .....	I <sub>DM</sub>	20		20		A
POWER DISSIPATION @ T <sub>C</sub> =25° C .....	P <sub>T</sub>	75	75	60	60	W
Derate above T <sub>C</sub> =25° C		0.6	0.6	0.48	0.48	W/°C
<b>OPERATING AND STORAGE</b>						
TEMPERATURE .....	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150		-55 to +150		°C

**RFM8N18L, RFM8N20L, RFP8N18L, RFP8N20L**

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**ELECTRICAL CHARACTERISTICS, At Case Temperature ( $T_C$ )=25° C unless otherwise specified.**

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			RFM8N18L RFP8N18L		RFM8N20L RFP8N20L		
			MIN.	MAX.	MIN.	MAX.	
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D=1\text{ mA}$ $V_{GS}=0$	180	—	200	—	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$ $I_D=1\text{ mA}$	1	2	1	2	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=145\text{ V}$ $V_{GS}=160\text{ V}$	—	1	—	—	$\mu\text{A}$
		$T_C=125^\circ\text{ C}$ $V_{DS}=145\text{ V}$ $V_{GS}=160\text{ V}$	—	50	—	50	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 10\text{ V}$ $V_{DS}=0$	—	100	—	100	nA
Drain-Source On Voltage	$V_{DS(on)}^a$	$I_D=4\text{ A}$ $V_{GS}=5\text{ V}$	—	2.0	—	2.0	V
		$I_D=8\text{ A}$ $V_{GS}=5\text{ V}$	—	4.6	—	4.6	
Static Drain-Source On Resistance	$r_{DS(on)}^a$	$I_D=4\text{ A}$ $V_{GS}=5\text{ V}$	—	0.5	—	0.5	$\Omega$
Forward Transconductance	$g_{fs}^a$	$V_{DS}=10\text{ V}$ $I_D=4\text{ A}$	3.0	—	3.0	—	mho
Input Capacitance	$C_{iss}$	$V_{DS}=25\text{ V}$	—	900	—	900	pF
Output Capacitance	$C_{oss}$	$V_{GS}=0\text{ V}$	—	250	—	250	
Reverse-Transfer Capacitance	$C_{rss}$	$f=1\text{ MHz}$	—	120	—	120	
Turn-On Delay Time	$t_d(on)$	$V_{DD}=50\text{ V}$ $I_D=4\text{ A}$ $R_{gen}=\infty$ $R_{gs}=6.25\ \Omega$ $V_{GS}=5\text{ V}$	15(typ)	45	15(typ)	45	ns
Rise Time	$t_r$		45(typ)	150	45(typ)	150	
Turn-Off Delay Time	$t_d(off)$		100(typ)	135	100(typ)	135	
Fall Time	$t_f$		60(typ)	105	60(typ)	105	
Thermal Resistance Junction-to-Case	$R\theta_{JC}$		RFM8N18L, RFM8N20L	—	1.67	—	
		RFP8N18L, RFP8N20L	—	2.083	—	2.083	

<sup>a</sup>Pulsed: Pulse duration = 300  $\mu\text{s}$  max., duty cycle = 2%.

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			RFM8N18L RFP8N18L		RFM8N20L RFP8N20L		
			MIN.	MAX.	MIN.	MAX.	
Diode Forward Voltage	$V_{SD}$	$I_{SD}=4\text{ A}$	—	1.4	—	1.4	V
Reverse Recovery Time	$t_{rr}$	$I_F=4\text{ A}$ $dI_F/dt=100\text{ A}/\mu\text{s}$	250(typ)		250(typ)		ns

<sup>a</sup>Pulse Test: Width  $\leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$ .

RFM8N18L, RFM8N20L, RFP8N18L, RFP8N20L

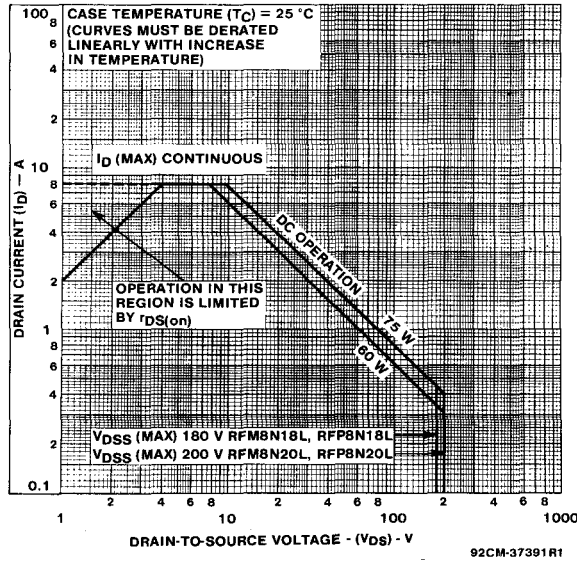


Fig. 1 — Maximum safe operating areas for all types.

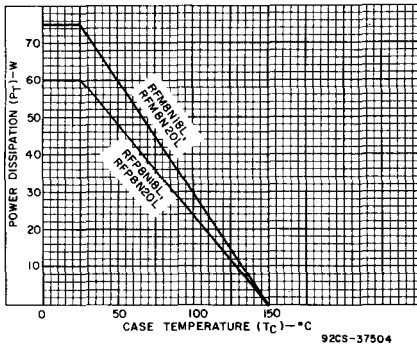


Fig. 2 — Power vs. temperature derating curve for all types.

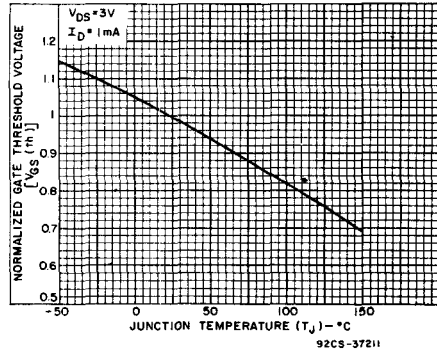


Fig. 3 — Typical normalized gate threshold voltage as a function of junction temperature for all types.

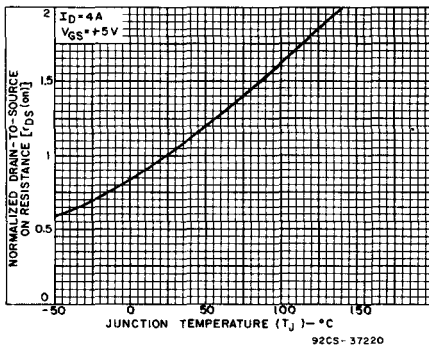


Fig. 4 — Normalized drain-to-source on resistance to junction temperature for all types.

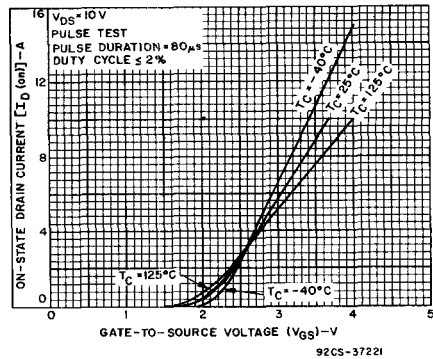


Fig. 5 — Typical transfer characteristics for all types.

RFM8N18L, RFM8N20L, RFP8N18L, RFP8N20L

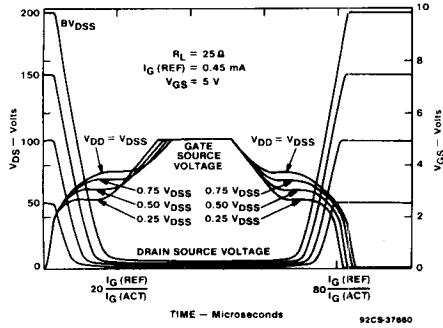


Fig. 6 - Normalized switching waveforms for constant gate-current. Refer to RCA application notes AN-7254 and AN-7260.

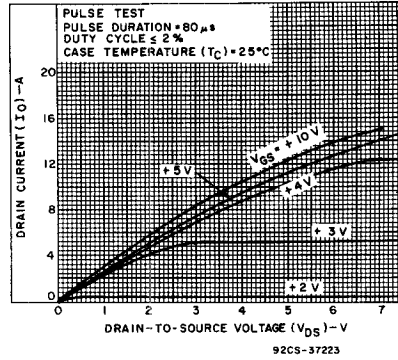


Fig. 7 - Typical saturation characteristics for all types.

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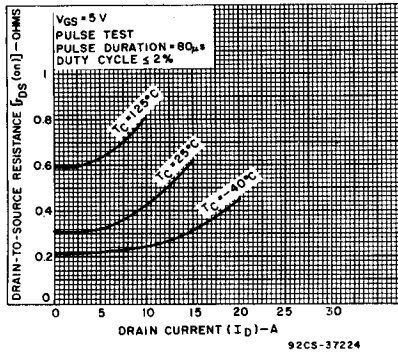


Fig. 8 - Typical drain-to-source on resistance as a function of drain current for all types.

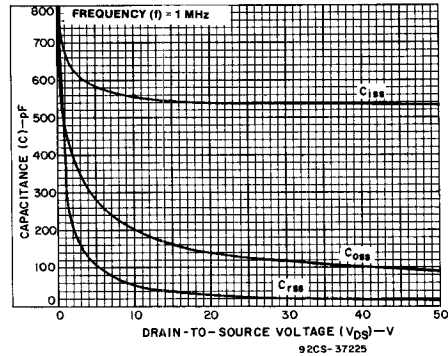


Fig. 9 - Capacitance as a function of drain-to-source voltage for all types.

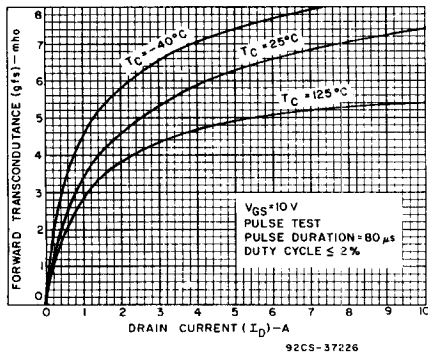


Fig. 10 - Typical forward transconductance as a function of drain current for all types.

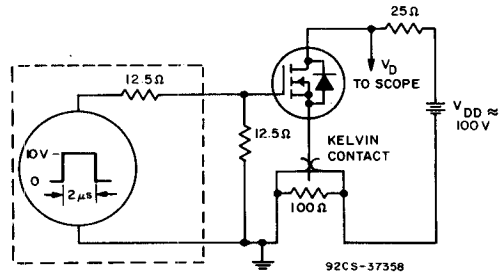


Fig. 11 - Switching Time Test Circuit.